Supporting Information

Robust Transparent and Conductive Gas Diffusion Multi-Barrier Based on Mg- and Al-Doped ZnO as **ITO-Free Electrodes for Organic Electronics**

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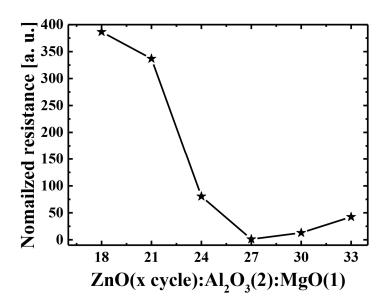


Figure S1. Electrical conductivity of the MAZO thin film as a function of the ZnO deposition cycle when the cyclic ratio of Al₂O₃:MgO was fixed as 2:1.

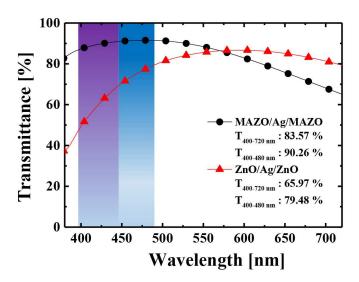


Figure S2. Calculated transmittances of the ZnO/Ag/ZnO and MAZO/Ag/MAZO structures in the visible wavelength.

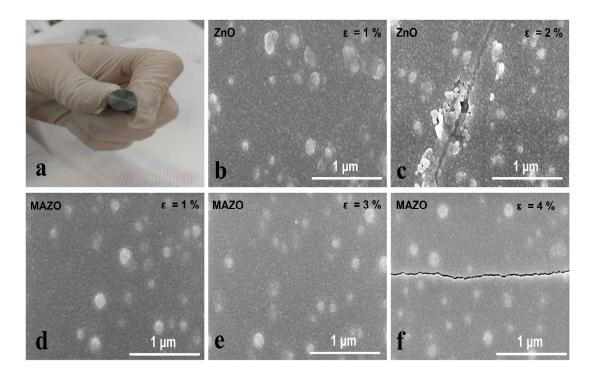


Figure S3. a) Photographs showing the tested samples fabricated on PET substrates under tensile bending tests. b) \sim f) Surface SEM images of ZnO and MAZO thin films on PET substrates as a function of bending strain.

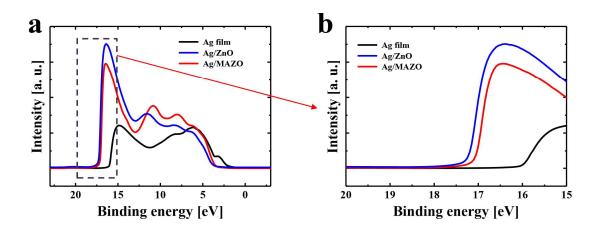


Figure S4. a) He(I) UPS spectra of Ag, Ag/ZnO, Ag/MAZO. b) Enlarged view of secondary electron cut-off regions.